



Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	16825
Number of Logic Elements/Cells	215360
Total RAM Bits	13455360
Number of I/O	285
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-FBGA, FCBGA
Supplier Device Package	484-FCBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7a200t-2sb484i

Table 3: DC Characteristics Over Recommended Operating Conditions (Cont'd)

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
n	Temperature diode ideality factor	–	1.010	–	–
r	Temperature diode series resistance	–	2	–	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. This measurement represents the die capacitance at the pad, not including the package.
3. Maximum value specified for worst case process at 25°C.
4. Termination resistance to a $V_{CCO}/2$ level.

Table 4: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for 3.3V HR I/O Banks⁽¹⁾

AC Voltage Overshoot	% of UI @–40°C to 100°C	AC Voltage Undershoot	% of UI @–40°C to 100°C
$V_{CCO} + 0.40$	100	–0.40	100
$V_{CCO} + 0.45$	100	–0.45	61.7
$V_{CCO} + 0.50$	100	–0.50	25.8
$V_{CCO} + 0.55$	100	–0.55	11.0
$V_{CCO} + 0.60$	46.6	–0.60	4.77
$V_{CCO} + 0.65$	21.2	–0.65	2.10
$V_{CCO} + 0.70$	9.75	–0.70	0.94
$V_{CCO} + 0.75$	4.55	–0.75	0.43
$V_{CCO} + 0.80$	2.15	–0.80	0.20
$V_{CCO} + 0.85$	1.02	–0.85	0.09
$V_{CCO} + 0.90$	0.49	–0.90	0.04
$V_{CCO} + 0.95$	0.24	–0.95	0.02

Notes:

1. A total of 200 mA per bank should not be exceeded.

Table 5: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	XC7A100T	155	155	155	108	mA
		XC7A200T	328	328	328	232	mA
I_{CCOQ}	Quiescent V_{CCO} supply current	XC7A100T	4	4	4	4	mA
		XC7A200T	5	5	5	5	mA
I_{CCAUXQ}	Quiescent V_{CCAUX} supply current	XC7A100T	36	36	36	36	mA
		XC7A200T	73	73	73	73	mA
$I_{CCBRAMQ}$	Quiescent V_{CCBRAM} supply current	XC7A100T	4	4	4	4	mA
		XC7A200T	11	11	11	11	mA

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperature (T_j) with single-ended SelectIO resources.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified.

Power-On/Off Power Supply Sequencing

The recommended power-on sequence is V_{CCINT} , V_{CCBRAM} , V_{CCAUX} , and V_{CCO} to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If V_{CCINT} and V_{CCBRAM} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously. If V_{CCAUX} and V_{CCO} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously.

For V_{CCO} voltages of 3.3V in HR I/O banks and configuration bank 0:

- The voltage difference between V_{CCO} and V_{CCAUX} must not exceed 2.625V for longer than $T_{VCCO2VCCAUX}$ for each power-on/off cycle to maintain device reliability levels.
- The $T_{VCCO2VCCAUX}$ time can be allocated in any percentage between the power-on and power-off ramps.

The recommended power-on sequence to achieve minimum current draw for the GTP transceivers is V_{CCINT} , $V_{MGTAVCC}$, $V_{MGTAVTT}$ OR $V_{MGTAVCC}$, V_{CCINT} , $V_{MGTAVTT}$. There is no recommended sequencing for $V_{MGTVCCAUX}$. Both $V_{MGTAVCC}$ and V_{CCINT} can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from $V_{MGTAVTT}$ can be higher than specifications during power-up and power-down.

- When $V_{MGTAVTT}$ is powered before $V_{MGTAVCC}$ and $V_{MGTAVTT} - V_{MGTAVCC} > 150$ mV and $V_{MGTAVCC} < 0.7$ V, the $V_{MGTAVTT}$ current draw can increase by 460 mA per transceiver during $V_{MGTAVCC}$ ramp up. The duration of the current draw can be up to $0.3 \times T_{MGTAVCC}$ (ramp time from GND to 90% of $V_{MGTAVCC}$). The reverse is true for power-down.
- When $V_{MGTAVTT}$ is powered before V_{CCINT} and $V_{MGTAVTT} - V_{CCINT} > 150$ mV and $V_{CCINT} < 0.7$ V, the $V_{MGTAVTT}$ current draw can increase by 50 mA per transceiver during V_{CCINT} ramp up. The duration of the current draw can be up to $0.3 \times T_{VCCINT}$ (ramp time from GND to 90% of V_{CCINT}). The reverse is true for power-down.

Table 6 shows the minimum current, in addition to I_{CCQ} , that is required by Artix-7 devices for proper power-on and configuration. If the current minimums shown in Table 5 and Table 6 are met, the device powers on after all four supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after V_{CCINT} is applied.

Once initialized and configured, use the Xilinx Power Estimator (XPE) tools to estimate current drain on these supplies.

Table 6: Power-On Current for Artix-7 Devices⁽¹⁾

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	$I_{CCBRAMMIN}$	Units
	Typ ⁽²⁾	Typ ⁽²⁾	Typ ⁽²⁾	Typ ⁽²⁾	
XC7A100T	$I_{CCINTQ} + 170$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7A200T	$I_{CCINTQ} + 340$	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 80$	mA

Notes:

1. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.
2. Typical values are specified at nominal voltage, 25°C.

Table 7: Power Supply Ramp Time

Symbol	Description	Conditions	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 90% of V_{CCINT}		0.2	50	ms
T_{VCCO}	Ramp time from GND to 90% of V_{CCO}		0.2	50	ms
T_{VCCAUX}	Ramp time from GND to 90% of V_{CCAUX}		0.2	50	ms
$T_{VCCBRAM}$	Ramp time from GND to 90% of V_{CCBRAM}		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625V$	$T_J = 100^{\circ}C^{(1)}$	–	500	ms
		$T_J = 85^{\circ}C^{(1)}$	–	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms

Notes:

1. Based on 240,000 power cycles with nominal V_{CCO} of 3.3V or 36,500 power cycles with worst case V_{CCO} of 3.465V.

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 8: SelectIO DC Input and Output Levels⁽¹⁾⁽²⁾

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA, Max	mA, Min
HSTL_I	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	8.00	-8.00
HSTL_I_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	8.00	-8.00
HSTL_II	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	16.00	-16.00
HSTL_II_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	16.00	-16.00
HSUL_12	-0.300	$V_{REF} - 0.130$	$V_{REF} + 0.130$	$V_{CCO} + 0.300$	20% V_{CCO}	80% V_{CCO}	0.10	-0.10
LVC MOS12	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 3	Note 3
LVC MOS15	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	25% V_{CCO}	75% V_{CCO}	Note 4	Note 4
LVC MOS18	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.450	$V_{CCO} - 0.450$	Note 5	Note 5
LVC MOS25	-0.300	0.7	1.700	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 4	Note 4
LVC MOS33	-0.300	0.8	2.000	3.450	0.400	$V_{CCO} - 0.400$	Note 4	Note 4
LV TTL	-0.300	0.8	2.000	3.450	0.400	2.400	Note 5	Note 5
MOBILE_DDR	-0.300	20% V_{CCO}	80% V_{CCO}	$V_{CCO} + 0.300$	10% V_{CCO}	90% V_{CCO}	0.10	-0.10
PCI33_3	-0.500	30% V_{CCO}	50% V_{CCO}	$V_{CCO} + 0.500$	10% V_{CCO}	90% V_{CCO}	1.50	-0.50
SSTL135	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	13.00	-13.00
SSTL135_R	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	8.90	-8.90
SSTL15	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	13.00	-13.00
SSTL15_R	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	8.90	-8.90
SSTL18_I	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.470$	$V_{CCO}/2 + 0.470$	8.00	-8.00
SSTL18_II	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.600$	$V_{CCO}/2 + 0.600$	13.40	-13.40

Notes:

1. Tested according to relevant specifications.
2. 3.3V and 2.5V standards are only supported in 3.3V I/O banks.
3. Supported drive strengths of 4, 8, or 12 mA in HR I/O banks.
4. Supported drive strengths of 4, 8, 12, or 16 mA in HR I/O banks.
5. Supported drive strengths of 4, 8, 12, 16, or 24 mA in HR I/O banks.
6. For detailed interface specific DC voltage levels, see [UG471](#): 7 Series FPGAs SelectIO Resources User Guide.

Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. [Table 12](#) correlates the current status of each Artix-7 device on a per speed grade basis.

Table 12: Artix-7 Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7A100T	-2L (0.9V)		-3, -2, -2L (1.0V), -1
XC7A200T	-2L (0.9V)		-3, -2, -2L (1.0V), -1

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

[Table 13](#) lists the production released Artix-7 device, speed grade, and the minimum corresponding supported speed specification version and ISE software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 13: Artix-7 Device Production Software and Speed Specification Release

Device	Speed Grade		
	1.0V		0.9V
	-3	-2/-2L	-1
XC7A100T	ISE 14.4 and Vivado 2012.4 with the 14.4/2012.4 device pack v1.07		-2L
XC7A200T	ISE 14.4 and Vivado 2012.4 with the 14.4/2012.4 device pack v1.07		

Notes:

- Blank entries indicate a device and/or speed grade in advance or preliminary status.

IOB Pad Input/Output/3-State

Table 16 summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 16: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
LVTTL_S4	1.26	1.34	1.41	1.58	3.80	3.93	4.18	4.41	4.37	4.59	5.01	5.06	ns
LVTTL_S8	1.26	1.34	1.41	1.58	3.54	3.66	3.92	4.15	4.11	4.32	4.75	4.80	ns
LVTTL_S12	1.26	1.34	1.41	1.58	3.52	3.65	3.90	4.13	4.09	4.31	4.73	4.78	ns
LVTTL_S16	1.26	1.34	1.41	1.58	3.07	3.19	3.45	3.68	3.64	3.85	4.28	4.33	ns
LVTTL_S24	1.26	1.34	1.41	1.58	3.29	3.41	3.67	3.90	3.86	4.07	4.50	4.55	ns
LVTTL_F4	1.26	1.34	1.41	1.58	3.26	3.38	3.64	3.86	3.83	4.04	4.46	4.51	ns
LVTTL_F8	1.26	1.34	1.41	1.58	2.74	2.87	3.12	3.35	3.31	3.52	3.95	4.00	ns
LVTTL_F12	1.26	1.34	1.41	1.58	2.73	2.85	3.10	3.33	3.29	3.51	3.93	3.98	ns
LVTTL_F16	1.26	1.34	1.41	1.58	2.55	2.68	2.93	3.16	3.12	3.34	3.76	3.81	ns
LVTTL_F24	1.26	1.34	1.41	1.58	2.52	2.65	2.90	3.22	3.09	3.31	3.73	3.87	ns
LVDS_25	0.73	0.81	0.88	0.90	1.29	1.41	1.67	1.86	1.86	2.07	2.49	2.51	ns
MINI_LVDS_25	0.73	0.81	0.88	0.90	1.27	1.40	1.65	1.88	1.84	2.06	2.48	2.53	ns
BLVDS_25	0.73	0.81	0.88	0.90	1.84	1.96	2.21	2.44	2.40	2.62	3.04	3.09	ns
RSDS_25 (point to point)	0.73	0.81	0.88	0.90	1.27	1.40	1.65	1.88	1.84	2.06	2.48	2.53	ns
PPDS_25	0.73	0.81	0.88	0.90	1.29	1.41	1.67	1.88	1.86	2.07	2.49	2.53	ns
TMDS_33	0.73	0.81	0.88	0.90	1.41	1.54	1.79	1.99	1.98	2.20	2.62	2.64	ns
PCI33_3	1.24	1.32	1.39	1.57	3.10	3.22	3.48	3.71	3.67	3.88	4.31	4.36	ns
HSUL_12	0.67	0.75	0.82	0.87	1.80	1.93	2.18	2.41	2.37	2.59	3.01	3.06	ns
DIFF_HSUL_12	0.68	0.76	0.83	0.88	1.80	1.93	2.18	2.21	2.37	2.59	3.01	2.86	ns
HSTL_I_S	0.67	0.75	0.82	0.87	1.62	1.74	1.99	2.19	2.19	2.40	2.82	2.84	ns
HSTL_II_S	0.65	0.73	0.80	0.85	1.41	1.54	1.79	1.99	1.98	2.20	2.62	2.64	ns
HSTL_I_18_S	0.67	0.75	0.82	0.87	1.29	1.41	1.67	1.86	1.86	2.07	2.49	2.51	ns
HSTL_II_18_S	0.66	0.75	0.81	0.87	1.41	1.54	1.79	1.97	1.98	2.20	2.62	2.62	ns
DIFF_HSTL_I_S	0.68	0.76	0.83	0.85	1.59	1.71	1.96	2.13	2.15	2.37	2.79	2.78	ns
DIFF_HSTL_II_S	0.68	0.76	0.83	0.85	1.51	1.63	1.88	2.07	2.08	2.29	2.71	2.72	ns
DIFF_HSTL_I_18_S	0.71	0.79	0.86	0.87	1.38	1.51	1.76	1.96	1.95	2.17	2.59	2.61	ns
DIFF_HSTL_II_18_S	0.70	0.78	0.85	0.87	1.46	1.58	1.84	2.00	2.03	2.24	2.67	2.65	ns
HSTL_I_F	0.67	0.75	0.82	0.87	1.10	1.22	1.48	1.69	1.67	1.88	2.31	2.34	ns

Input/Output Logic Switching Characteristics

Table 18: ILOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T _{ICE1CK} /T _{ICKCE1}	CE1 pin setup/hold with respect to CLK	0.48/0.02	0.54/0.02	0.76/0.02	0.40/−0.07	ns
T _{ISRCK} /T _{ICKSR}	SR pin setup/hold with respect to CLK	0.60/0.01	0.70/0.01	1.13/0.01	0.88/−0.35	ns
T _{IDOCK} /T _{IOCKD}	D pin setup/hold with respect to CLK without Delay	0.01/0.27	0.01/0.29	0.01/0.33	0.01/0.33	ns
T _{IDOCKD} /T _{IOCKDD}	DDLY pin setup/hold with respect to CLK (using IDELAY)	0.02/0.27	0.02/0.29	0.02/0.33	0.01/0.33	ns
Combinatorial						
T _{IDI}	D pin to O pin propagation delay, no Delay	0.11	0.11	0.13	0.14	ns
T _{IDID}	DDLY pin to O pin propagation delay (using IDELAY)	0.11	0.12	0.14	0.15	ns
Sequential Delays						
T _{IDLO}	D pin to Q1 pin using flip-flop as a latch without Delay	0.41	0.44	0.51	0.54	ns
T _{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY)	0.41	0.44	0.51	0.55	ns
T _{ICKQ}	CLK to Q outputs	0.53	0.57	0.66	0.71	ns
T _{RQ_ILOGIC}	SR pin to OQ/TQ out	0.96	1.08	1.32	1.32	ns
T _{GSRQ_ILOGIC}	Global set/reset to Q outputs	7.60	7.60	10.51	11.39	ns
Set/Reset						
T _{RPW_ILOGIC}	Minimum pulse width, SR inputs	0.61	0.72	0.72	0.68	ns, Min

Table 19: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T _{ODCK} /T _{OCKD}	D1/D2 pins setup/hold with respect to CLK	0.67/−0.11	0.71/−0.11	0.84/−0.11	0.60/−0.18	ns
T _{OOCECK} /T _{OCKOCE}	OCE pin setup/hold with respect to CLK	0.32/0.58	0.34/0.58	0.51/0.58	0.21/−0.10	ns
T _{OSRCK} /T _{OCKSR}	SR pin setup/hold with respect to CLK	0.37/0.21	0.44/0.21	0.80/0.21	0.62/−0.25	ns
T _{OTCK} /T _{OCKT}	T1/T2 pins setup/hold with respect to CLK	0.69/−0.14	0.73/−0.14	0.89/−0.14	0.60/−0.18	ns
T _{OTCECK} /T _{OCKTCE}	TCE pin setup/hold with respect to CLK	0.32/0.01	0.34/0.01	0.51/0.01	0.22/−0.10	ns
Combinatorial						
T _{ODQ}	D1 to OQ out or T1 to TQ out	0.83	0.96	1.16	1.36	ns
Sequential Delays						
T _{OCKQ}	CLK to OQ/TQ out	0.47	0.49	0.56	0.63	ns
T _{RQ_OLOGIC}	SR pin to OQ/TQ out	0.72	0.80	0.95	1.12	ns
T _{GSRQ_OLOGIC}	Global set/reset to Q outputs	7.60	7.60	10.51	11.39	ns
Set/Reset						
T _{RPW_OLOGIC}	Minimum pulse width, SR inputs	0.64	0.74	0.74	0.68	ns, Min

Input/Output Delay Switching Characteristics

Table 22: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
IDELAYCTRL						
T _{DLYCCO_RDY}	Reset to ready for IDELAYCTRL	3.67	3.67	3.67	3.22	μs
F _{IDELAYCTRL_REF}	Attribute REFCLK frequency = 200.00 ⁽¹⁾	200.00	200.00	200.00	200.00	MHz
	Attribute REFCLK frequency = 300.00 ⁽¹⁾	300.00	300.00	N/A	N/A	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum Reset pulse width	59.28	59.28	59.28	52.00	ns
IDELAY						
T _{IDELAYRESOLUTION}	IDELAY chain delay resolution	1/(32 x 2 x F _{REF})				ps
T _{IDELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽³⁾	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽⁴⁾	±9	±9	±9	±9	ps per tap
T _{IDELAY_CLK_MAX}	Maximum frequency of CLK input to IDELAY	680.00	680.00	600.00	520.00	MHz
T _{IDCCK_CE} / T _{IDCKC_CE}	CE pin setup/hold with respect to C for IDELAY	0.12/0.11	0.16/0.13	0.21/0.16	0.14/0.16	ns
T _{IDCCK_INC} / T _{IDCKC_INC}	INC pin setup/hold with respect to C for IDELAY	0.12/0.16	0.14/0.18	0.16/0.22	0.10/0.23	ns
T _{IDCCK_RST} / T _{IDCKC_RST}	RST pin setup/hold with respect to C for IDELAY	0.15/0.09	0.16/0.11	0.18/0.14	0.22/0.19	ns
T _{IDDO_IDATAIN}	Propagation delay through IDELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE.
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY tap setting. See TRACE report for actual values.

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 25: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.98	1.09	1.32	1.54	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	1.37	1.53	1.86	2.18	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS_LRAM} /T _{DH_LRAM}	A – D inputs to CLK	0.54/0.28	0.60/0.30	0.72/0.35	0.96/0.40	ns, Min
T _{AS_LRAM} /T _{AH_LRAM}	Address An inputs to clock	0.27/0.55	0.30/0.60	0.37/0.70	0.43/0.71	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.69/0.18	0.77/0.21	0.94/0.26	1.11/0.29	ns, Min
T _{WS_LRAM} /T _{WH_LRAM}	WE input to clock	0.38/0.10	0.43/0.12	0.53/0.17	0.62/0.13	ns, Min
T _{CECK_LRAM} / T _{CKCE_LRAM}	CE input to CLK	0.39/0.10	0.44/0.11	0.53/0.17	0.63/0.12	ns, Min
Clock CLK						
T _{MPW_LRAM}	Minimum pulse width	1.05	1.13	1.25	0.82	ns, Min
T _{MCP}	Minimum clock period	2.10	2.26	2.50	1.64	ns, Min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 26: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	1.19	1.33	1.61	1.89	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.58	1.77	2.15	2.53	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	1.12	1.23	1.46	1.68	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS_SHFREG} / T _{WH_SHFREG}	WE input	0.37/0.10	0.41/0.12	0.51/0.17	0.59/0.13	ns, Min
T _{CECK_SHFREG} / T _{CKCE_SHFREG}	CE input to CLK	0.37/0.10	0.42/0.11	0.52/0.17	0.60/0.12	ns, Min
T _{DS_SHFREG} / T _{DH_SHFREG}	A – D inputs to CLK	0.33/0.34	0.37/0.37	0.44/0.43	0.54/0.47	ns, Min
Clock CLK						
T _{MPW_SHFREG}	Minimum pulse width	0.77	0.86	0.98	1.04	ns, Min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

Block RAM and FIFO Switching Characteristics

Table 27: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.85	2.13	2.46	2.87	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.64	0.74	0.89	1.02	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.77	3.04	3.84	5.30	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.73	0.81	0.94	1.11	ns, Max
T _{RCKO_DO_CASCOU} and T _{RCKO_DO_CASCOU_REG}	Clock CLK to DOUT output with cascade (without output register) ⁽²⁾	2.61	2.88	3.30	3.76	ns, Max
	Clock CLK to DOUT output with cascade (with output register) ⁽⁴⁾	1.16	1.28	1.46	1.56	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.76	0.87	1.05	1.14	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.94	1.02	1.15	1.30	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.78	0.85	0.94	1.10	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (without output register)	2.56	2.81	3.55	4.90	ns, Max
	Clock CLK to BITERR (with output register)	0.68	0.76	0.89	1.05	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.75	0.88	1.07	1.15	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.84	0.93	1.08	1.29	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKCK_ADDRA} /T _{RCKKC_ADDRA}	ADDR inputs ⁽⁸⁾	0.45/0.31	0.49/0.33	0.57/0.36	0.77/0.45	ns, Min
T _{RDCK_DI_WF_NC} / T _{RCKD_DI_WF_NC}	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode ⁽⁹⁾	0.58/0.60	0.65/0.63	0.74/0.67	0.92/0.76	ns, Min
T _{RDCK_DI_RF} /T _{RCKD_DI_RF}	Data input setup/hold time when block RAM is configured in READ_FIRST mode ⁽⁹⁾	0.20/0.29	0.22/0.34	0.25/0.41	0.29/0.38	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.50/0.43	0.55/0.46	0.63/0.50	0.78/0.54	ns, Min
T _{RDCK_DI_ECCW} / T _{RCKD_DI_ECCW}	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.93/0.43	1.02/0.46	1.17/0.50	1.38/0.48	ns, Min
T _{RDCK_DI_ECC_FIFO} / T _{RCKD_DI_ECC_FIFO}	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	1.04/0.56	1.15/0.59	1.32/0.64	1.55/0.77	ns, Min
T _{RCKCK_INJECTBITERR} / T _{RCKKC_INJECTBITERR}	Inject single/double bit error in ECC mode	0.58/0.35	0.64/0.37	0.74/0.40	0.92/0.48	ns, Min
T _{RCKCK_EN} /T _{RCKKC_EN}	Block RAM enable (EN) input	0.35/0.20	0.39/0.21	0.45/0.23	0.57/0.26	ns, Min
T _{RCKCK_REGCE} /T _{RCKKC_REGCE}	CE input of output register	0.24/0.15	0.29/0.15	0.36/0.16	0.40/0.19	ns, Min
T _{RCKCK_RSTREG} /T _{RCKKC_RSTREG}	Synchronous RSTREG input	0.29/0.07	0.32/0.07	0.35/0.07	0.41/0.07	ns, Min

DSP48E1 Switching Characteristics

Table 28: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock						
T _{DSPDCK_A_AREG} / T _{DSPCKD_A_AREG}	A input to A register CLK	0.26/ 0.12	0.30/ 0.13	0.37/ 0.14	0.45/ 0.14	ns
T _{DSPDCK_B_BREG} /T _{DSPCKD_B_BREG}	B input to B register CLK	0.33/ 0.15	0.38/ 0.16	0.45/ 0.18	0.60/ 0.19	ns
T _{DSPDCK_C_CREG} /T _{DSPCKD_C_CREG}	C input to C register CLK	0.17/ 0.17	0.20/ 0.19	0.24/ 0.21	0.34/ 0.29	ns
T _{DSPDCK_D_DREG} /T _{DSPCKD_D_DREG}	D input to D register CLK	0.25/ 0.25	0.32/ 0.27	0.42/ 0.27	0.54/ 0.23	ns
T _{DSPDCK_ACIN_AREG} /T _{DSPCKD_ACIN_AREG}	ACIN input to A register CLK	0.23/ 0.12	0.27/ 0.13	0.32/ 0.14	0.36/ 0.14	ns
T _{DSPDCK_BCIN_BREG} /T _{DSPCKD_BCIN_BREG}	BCIN input to B register CLK	0.25/ 0.15	0.29/ 0.16	0.36/ 0.18	0.41/ 0.19	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock						
T _{DSPDCK_{A, B}_MREG_MULT} / T _{DSPCKD_B_MREG_MULT}	{A, B} input to M register CLK using multiplier	2.40/ −0.01	2.76/ −0.01	3.29/ −0.01	4.31/ −0.07	ns
T _{DSPDCK_{A, B}_ADREG} / T _{DSPCKD_D_ADREG}	{A, D} input to AD register CLK	1.29/ −0.02	1.48/ −0.02	1.76/ −0.02	2.29/ −0.27	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock						
T _{DSPDCK_{A, B}_PREG_MULT} / T _{DSPCKD_{A, B}_PREG_MULT}	{A, B} input to P register CLK using multiplier	4.02/ −0.28	4.60/ −0.28	5.48/ −0.28	6.95/ −0.48	ns
T _{DSPDCK_D_PREG_MULT} / T _{DSPCKD_D_PREG_MULT}	D input to P register CLK using multiplier	3.93/ −0.73	4.50/ −0.73	5.35/ −0.73	6.73/ −1.68	ns
T _{DSPDCK_{A, B}_PREG} / T _{DSPCKD_{A, B}_PREG}	A or B input to P register CLK not using multiplier	1.73/ −0.28	1.98/ −0.28	2.35/ −0.28	2.80/ −0.48	ns
T _{DSPDCK_C_PREG} / T _{DSPCKD_C_PREG}	C input to P register CLK not using multiplier	1.54/ −0.26	1.76/ −0.26	2.10/ −0.26	2.54/ −0.45	ns
T _{DSPDCK_PCIN_PREG} / T _{DSPCKD_PCIN_PREG}	PCIN input to P register CLK	1.32/ −0.15	1.51/ −0.15	1.80/ −0.15	2.13/ −0.25	ns
Setup and Hold Times of the CE Pins						
T _{DSPDCK_{CEA;CEB}_{AREG;BREG}} / T _{DSPCKD_{CEA;CEB}_{AREG;BREG}}	{CEA; CEB} input to {A; B} register CLK	0.35/ 0.06	0.42/ 0.08	0.52/ 0.11	0.64/ 0.11	ns
T _{DSPDCK_CEC_CREG} / T _{DSPCKD_CEC_CREG}	CEC input to C register CLK	0.28/ 0.10	0.34/ 0.11	0.42/ 0.13	0.49/ 0.16	ns
T _{DSPDCK_CED_DREG} / T _{DSPCKD_CED_DREG}	CED input to D register CLK	0.36/ −0.03	0.43/ −0.03	0.52/ −0.03	0.68/ 0.14	ns
T _{DSPDCK_CEM_MREG} / T _{DSPCKD_CEM_MREG}	CEM input to M register CLK	0.17/ 0.18	0.21/ 0.20	0.27/ 0.23	0.45/ 0.29	ns
T _{DSPDCK_CEP_PREG} / T _{DSPCKD_CEP_PREG}	CEP input to P register CLK	0.36/ 0.01	0.43/ 0.01	0.53/ 0.01	0.63/ 0.00	ns

Table 28: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of the RST Pins						
$T_{\text{DSPDCK}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}/T_{\text{DSPCKD}_{\{\text{RSTA}; \text{RSTB}\}}_{\{\text{AREG}; \text{BREG}\}}}$	{RSTA, RSTB} input to {A, B} register CLK	0.41/ 0.11	0.46/ 0.13	0.55/ 0.15	0.63/ 0.40	ns
$T_{\text{DSPDCK_RSTC_CREG}}/T_{\text{DSPCKD_RSTC_CREG}}$	RSTC input to C register CLK	0.07/ 0.10	0.08/ 0.11	0.09/ 0.12	0.13/ 0.11	ns
$T_{\text{DSPDCK_RSTD_DREG}}/T_{\text{DSPCKD_RSTD_DREG}}$	RSTD input to D register CLK	0.44/ 0.07	0.50/ 0.08	0.59/ 0.09	0.67/ 0.08	ns
$T_{\text{DSPDCK_RSTM_MREG}}/T_{\text{DSPCKD_RSTM_MREG}}$	RSTM input to M register CLK	0.21/ 0.22	0.23/ 0.24	0.27/ 0.28	0.28/ 0.35	ns
$T_{\text{DSPDCK_RSTP_PREG}}/T_{\text{DSPCKD_RSTP_PREG}}$	RSTP input to P register CLK	0.27/ 0.01	0.30/ 0.01	0.35/ 0.01	0.43/ 0.00	ns
Combinatorial Delays from Input Pins to Output Pins						
$T_{\text{DSPDO_A_CARRYOUT_MULT}}$	A input to CARRYOUT output using multiplier	3.79	4.35	5.18	6.61	ns
$T_{\text{DSPDO_D_P_MULT}}$	D input to P output using multiplier	3.72	4.26	5.07	6.41	ns
$T_{\text{DSPDO_B_P}}$	B input to P output not using multiplier	1.53	1.75	2.08	2.48	ns
$T_{\text{DSPDO_C_P}}$	C input to P output	1.33	1.53	1.82	2.22	ns
Combinatorial Delays from Input Pins to Cascading Output Pins						
$T_{\text{DSPDO}_{\{\text{A}; \text{B}\}}_{\{\text{ACOUT}; \text{BCOUT}\}}}$	{A, B} input to {ACOUT, BCOUT} output	0.55	0.63	0.74	0.87	ns
$T_{\text{DSPDO}_{\{\text{A}; \text{B}\}}_{\text{CARRYCASCOUT_MULT}}}$	{A, B} input to CARRYCASCOUT output using multiplier	4.06	4.65	5.54	7.03	ns
$T_{\text{DSPDO_D_CARRYCASCOUT_MULT}}$	D input to CARRYCASCOUT output using multiplier	3.97	4.54	5.40	6.81	ns
$T_{\text{DSPDO}_{\{\text{A}; \text{B}\}}_{\text{CARRYCASCOUT}}}$	{A, B} input to CARRYCASCOUT output not using multiplier	1.77	2.03	2.41	2.88	ns
$T_{\text{DSPDO_C_CARRYCASCOUT}}$	C input to CARRYCASCOUT output	1.58	1.81	2.15	2.62	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins						
$T_{\text{DSPDO_ACIN_P_MULT}}$	ACIN input to P output using multiplier	3.65	4.19	5.00	6.40	ns
$T_{\text{DSPDO_ACIN_P}}$	ACIN input to P output not using multiplier	1.37	1.57	1.88	2.44	ns
$T_{\text{DSPDO_ACIN_ACOUT}}$	ACIN input to ACOUT output	0.38	0.44	0.53	0.63	ns
$T_{\text{DSPDO_ACIN_CARRYCASCOUT_MULT}}$	ACIN input to CARRYCASCOUT output using multiplier	3.90	4.47	5.33	6.79	ns
$T_{\text{DSPDO_ACIN_CARRYCASCOUT}}$	ACIN input to CARRYCASCOUT output not using multiplier	1.61	1.85	2.21	2.84	ns
$T_{\text{DSPDO_PCIN_P}}$	PCIN input to P output	1.11	1.28	1.52	1.82	ns
$T_{\text{DSPDO_PCIN_CARRYCASCOUT}}$	PCIN input to CARRYCASCOUT output	1.36	1.56	1.85	2.21	ns
Clock to Outs from Output Register Clock to Output Pins						
$T_{\text{DSPCKO_P_PREG}}$	CLK PREG to P output	0.33	0.37	0.44	0.54	ns
$T_{\text{DSPCKO_CARRYCASCOUT_PREG}}$	CLK PREG to CARRYCASCOUT output	0.52	0.59	0.69	0.84	ns

Clock Buffers and Networks

Table 29: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$T_{BCCCK_CE}/T_{BCCCK_CE}^{(1)}$	CE pins setup/hold	0.12/0.39	0.13/0.40	0.16/0.41	0.31/0.17	ns
$T_{BCCCK_S}/T_{BCCCK_S}^{(1)}$	S pins setup/hold	0.12/0.39	0.13/0.40	0.16/0.41	0.31/0.17	ns
$T_{BCKO_O}^{(2)}$	BUFGCTRL delay from I0/I1 to O	0.08	0.09	0.10	0.14	ns
Maximum Frequency						
F_{MAX_BUFG}	Global clock tree (BUFG)	628.00	628.00	464.00	394.00	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCCK_S} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BCKO_O} (BUFG delay from I0 to O) values are the same as T_{BCKO_O} values.

Table 30: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{BIOCKO_O}	Clock to out delay from I to O	1.11	1.26	1.54	1.56	ns
Maximum Frequency						
F_{MAX_BUFIO}	I/O clock tree (BUFIO)	680.00	680.00	600.00	600.00	MHz

Table 31: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{BRCKO_O}	Clock to out delay from I to O	0.64	0.76	0.99	1.24	ns
$T_{BRCKO_O_BYP}$	Clock to out delay from I to O with Divide Bypass attribute set	0.34	0.39	0.52	0.72	ns
T_{BRDO_O}	Propagation delay from CLR to O	0.81	0.85	1.09	0.96	ns
Maximum Frequency						
$F_{MAX_BUFR}^{(1)}$	Regional clock tree (BUFR)	420.00	375.00	315.00	315.00	MHz

Notes:

1. The maximum input frequency to the BUFR and BUFMR is the BUFIO F_{MAX} frequency.

Table 32: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{BHCKO_O}	BUFH delay from I to O	0.10	0.11	0.13	0.16	ns
T_{BHCK_CE}/T_{BHCK_CE}	CE pin setup and hold	0.19/0.13	0.22/0.15	0.28/0.21	0.35/0.08	ns
Maximum Frequency						
F_{MAX_BUFH}	Horizontal clock buffer (BUFH)	628.00	628.00	464.00	394.00	MHz

Table 33: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
T_{DCD_CLK}	Global clock tree duty-cycle distortion ⁽¹⁾	All	0.20	0.20	0.20	0.25	ns
T_{CKSKEW}	Global clock tree skew ⁽²⁾	XC7A100T	0.27	0.33	0.36	0.48	ns
		XC7A200T	0.40	0.48	0.54	0.69	ns
T_{DCD_BUFIO}	I/O clock tree duty cycle distortion	All	0.14	0.14	0.14	0.14	ns
$T_{BUFIOSKEW}$	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.03	ns
T_{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.18	0.18	0.18	0.18	ns

Notes:

- These parameters represent the worst-case duty cycle distortion observable at the I/O flip flops. For all I/O standards, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
- The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

MMCM Switching Characteristics

Table 34: MMCM Specification

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$MMCM_F_{INMAX}$	Maximum input clock frequency	800.00	800.00	800.00	800.00	MHz
$MMCM_F_{INMIN}$	Minimum input clock frequency	10.00	10.00	10.00	10.00	MHz
$MMCM_F_{INJITTER}$	Maximum input clock period jitter	< 20% of clock input period or 1 ns Max				
$MMCM_F_{INDUTY}$	Allowable input duty cycle: 10—49 MHz	25	25	25	25	%
	Allowable input duty cycle: 50—199 MHz	30	30	30	30	%
	Allowable input duty cycle: 200—399 MHz	35	35	35	35	%
	Allowable input duty cycle: 400—499 MHz	40	40	40	40	%
	Allowable input duty cycle: >500 MHz	45	45	45	45	%
$MMCM_F_{MIN_PSCLK}$	Minimum dynamic phase-shift clock frequency	0.01	0.01	0.01	0.01	MHz
$MMCM_F_{MAX_PSCLK}$	Maximum dynamic phase-shift clock frequency	550.00	500.00	450.00	450.00	MHz
$MMCM_F_{VCOMIN}$	Minimum MMCM VCO frequency	600.00	600.00	600.00	600.00	MHz
$MMCM_F_{VCOMAX}$	Maximum MMCM VCO frequency	1600.00	1440.00	1200.00	1200.00	MHz

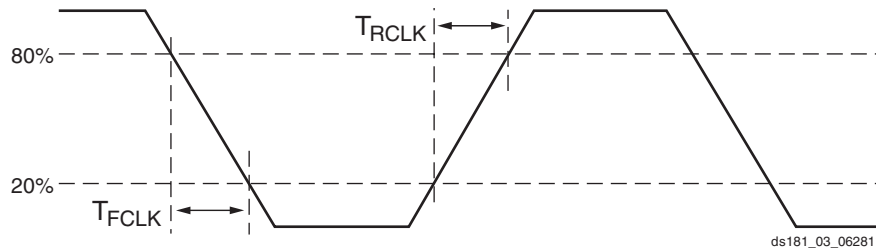


Figure 3: Reference Clock Timing Parameters

Table 52: GTP Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T_{LOCK}	Initial PLL lock		–	–	1	ms
T_{DLOCK}	Clock recovery phase acquisition and adaptation time.	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	–	50,000	2.3×10^6	UI

Table 53: GTP Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Conditions	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
F_{TXOUT}	TXOUTCLK maximum frequency		412.500	412.500	234.375	234.375	MHz
F_{RXOUT}	RXOUTCLK maximum frequency		412.500	412.500	234.375	234.375	MHz
F_{TXIN}	TXUSRCLK maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F_{RXIN}	RXUSRCLK maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F_{TXIN2}	TXUSRCLK2 maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F_{RXIN2}	RXUSRCLK2 maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz

Notes:

1. Clocking must be implemented as described in [UG482](#): 7 Series FPGAs GTP Transceiver User Guide.

Table 54: GTP Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTPTX}	Serial data rate range		0.500	–	F _{GTPMAX}	Gb/s
T _{RTX}	TX rise time	20%–80%	–	50	–	ps
T _{FTX}	TX fall time	20%–80%	–	50	–	ps
T _{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		–	–	500	ps
V _{TXOOBVDPP}	Electrical idle amplitude		–	–	20	mV
T _{TXOOBTRANSITION}	Electrical idle transition time		–	–	140	ns
TJ _{6.6}	Total Jitter ⁽²⁾⁽³⁾	6.6 Gb/s	–	–	0.30	UI
DJ _{6.6}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.15	UI
TJ _{5.0}	Total Jitter ⁽²⁾⁽³⁾	5.0 Gb/s	–	–	0.30	UI
DJ _{5.0}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.15	UI
TJ _{4.25}	Total Jitter ⁽²⁾⁽³⁾	4.25 Gb/s	–	–	0.30	UI
DJ _{4.25}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.15	UI
TJ _{3.75}	Total Jitter ⁽²⁾⁽³⁾	3.75 Gb/s	–	–	0.30	UI
DJ _{3.75}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.15	UI
TJ _{3.2}	Total Jitter ⁽²⁾⁽³⁾	3.20 Gb/s ⁽⁴⁾	–	–	0.2	UI
DJ _{3.2}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.1	UI
TJ _{3.2L}	Total Jitter ⁽²⁾⁽³⁾	3.20 Gb/s ⁽⁵⁾	–	–	0.32	UI
DJ _{3.2L}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.16	UI
TJ _{2.5}	Total Jitter ⁽²⁾⁽³⁾	2.5 Gb/s ⁽⁶⁾	–	–	0.20	UI
DJ _{2.5}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.08	UI
TJ _{1.25}	Total Jitter ⁽²⁾⁽³⁾	1.25 Gb/s ⁽⁷⁾	–	–	0.15	UI
DJ _{1.25}	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.06	UI
TJ ₅₀₀	Total Jitter ⁽²⁾⁽³⁾	500 Mb/s	–	–	0.1	UI
DJ ₅₀₀	Deterministic Jitter ⁽²⁾⁽³⁾		–	–	0.03	UI

Notes:

- Using same REFCLK input with TX phase alignment enabled for up to four consecutive transmitters (one fully populated GTP Quad).
- Using PLL[0/1]_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
- All jitter values are based on a bit-error ratio of 1e⁻¹².
- PLL frequency at 3.2 GHz and TXOUT_DIV = 2.
- PLL frequency at 1.6 GHz and TXOUT_DIV = 1.
- PLL frequency at 2.5 GHz and TXOUT_DIV = 2.
- PLL frequency at 2.5 GHz and TXOUT_DIV = 4.

GTP Transceiver Protocol Jitter Characteristics

For Table 56 through Table 60, the [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) contains recommended settings for optimal usage of protocol specific characteristics.

Table 56: Gigabit Ethernet Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
Gigabit Ethernet Transmitter Jitter Generation				
Total transmitter jitter (T _{TJ})	1250	–	0.24	UI
Gigabit Ethernet Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	1250	0.749	–	UI

Table 57: XAUI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
XAUI Transmitter Jitter Generation				
Total transmitter jitter (T _{TJ})	3125	–	0.35	UI
XAUI Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	3125	0.65	–	UI

Table 58: PCI Express Protocol Characteristics⁽¹⁾

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
PCI Express Transmitter Jitter Generation					
PCI Express Gen 1	Total transmitter jitter	2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter	5000	–	0.25	UI
PCI Express Receiver High Frequency Jitter Tolerance					
PCI Express Gen 1	Total receiver jitter tolerance	2500	0.65	–	UI
PCI Express Gen 2 ⁽²⁾	Receiver inherent timing error	5000	0.40	–	UI
	Receiver inherent deterministic timing error		0.30	–	UI

Notes:

1. Tested per card electromechanical (CEM) methodology.
2. Using common REFCLK.

Table 59: CEI-6G Protocol Characteristics

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
CEI-6G Transmitter Jitter Generation					
Total transmitter jitter ⁽¹⁾	4976–6375	CEI-6G-SR	–	0.3	UI
CEI-6G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽¹⁾	4976–6375	CEI-6G-SR	0.6	–	UI

Notes:

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.

XADC Specifications

Table 62: XADC Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
V _{CCADC} = 1.8V ± 5%, V _{REFP} = 1.25V, V _{REFN} = 0V, ADCCLK = 26 MHz, T _j = −40°C to 100°C, Typical values at T _j =+40°C						
ADC Accuracy ⁽¹⁾						
Resolution			12	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	±2	LSBs
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	LSBs
Offset Error		Unipolar operation	–	–	±8	LSBs
		Bipolar operation	–	–	±4	LSBs
Gain Error			–	–	±0.5	%
Offset Matching			–	–	4	LSBs
Gain Matching			–	–	0.3	%
Sample Rate			0.1	–	1	MS/s
Signal to Noise Ratio ⁽²⁾	SNR	F _{SAMPLE} = 500KS/s, F _{IN} = 20KHz	60	–	–	dB
RMS Code Noise		External 1.25V reference	–	–	2	LSBs
		On-chip reference	–	3	–	LSBs
Total Harmonic Distortion ⁽²⁾	THD	F _{SAMPLE} = 500KS/s, F _{IN} = 20KHz	70	–	–	dB
ADC Accuracy at Extended Temperatures (-55°C to 125°C)						
Resolution			10	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	±1	LSB (at 10 bits)
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	
Analog Inputs ⁽³⁾						
ADC Input Ranges		Unipolar operation	0	–	1	V
		Bipolar operation	−0.5	–	+0.5	V
		Unipolar common mode range (FS input)	0	–	+0.5	V
		Bipolar common mode range (FS input)	+0.5	–	+0.6	V
Maximum External Channel Input Ranges		Adjacent analog channels set within these ranges should not corrupt measurements on adjacent channels	−0.1	–	V _{CCADC}	V
Auxiliary Channel Full Resolution Bandwidth	FRBW		250	–	–	KHz
On-Chip Sensors						
Temperature Sensor Error		T _j = −40°C to 100°C	–	–	±4	°C
		T _j = −55°C to +125°C	–	–	±6	°C
Supply Sensor Error		Measurement range of V _{CCAUX} 1.8V ±5% T _j = −40°C to +100°C	–	–	±1	%
		Measurement range of V _{CCAUX} 1.8V ±5% T _j = −55°C to +125°C	–	–	±2	%
Conversion Rate ⁽⁴⁾						
Conversion Time - Continuous	t _{CONV}	Number of ADCCLK cycles	26	–	32	Cycles
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	Cycles
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	250	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	26	MHz

Table 63: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Internal Configuration Access Port						
F _{ICAPCK}	Internal configuration access port (ICAPE2) clock frequency	100.00	100.00	100.00	70.00	MHz, Max
Master/Slave Serial Mode Programming Switching						
T _{DCCK} /T _{CCKD}	DIN setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	5.00/0.00	ns, Min
T _{CCO}	DOUT clock to out	8.00	8.00	8.00	9.00	ns, Max
SelectMAP Mode Programming Switching						
T _{SMDCCK} /T _{SMCCCKD}	D[31:00] setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	4.50/0.00	ns, Min
T _{SMCSCCK} /T _{SMCCCKCS}	CSI_B setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	5.00/0.00	ns, Min
T _{SMWCCK} /T _{SMCCCKW}	RDWR_B setup/hold	10.00/0.00	10.00/0.00	10.00/0.00	12.00/0.00	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)	7.00	7.00	7.00	8.00	ns, Max
T _{SMCO}	D[31:00] clock to out in readback	8.00	8.00	8.00	10.00	ns, Max
F _{RBCK}	Readback frequency	100.00	100.00	100.00	70.00	MHz, Max
Boundary-Scan Port Timing Specifications						
T _{TAPTCK} /T _{TCKTAP}	TMS and TDI setup/hold	3.00/2.00	3.00/2.00	3.00/2.00	3.00/2.00	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output	7.00	7.00	7.00	8.50	ns, Max
F _{TCK}	TCK frequency	66.00	66.00	66.00	50.00	MHz, Max
BPI Flash Master Mode Programming Switching						
T _{BPICCO} ⁽²⁾	A[28:00], RS[1:0], FCS_B, FOE_B, FWE_B, ADV_B clock to out	8.50	8.50	8.50	10.00	ns, Max
T _{BPIDCC} /T _{BPICCD}	D[15:00] setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	4.50/0.00	ns, Min
SPI Flash Master Mode Programming Switching						
T _{SPIDCC} /T _{SPICCD}	D[03:00] setup/hold	3.00/0.00	3.00/0.00	3.00/0.00	3.00/0.00	ns, Min
T _{SPICCM}	MOSI clock to out	8.00	8.00	8.00	9.00	ns, Max
T _{SPICCF}	FCS_B clock to out	8.00	8.00	8.00	9.00	ns, Max

Notes:

- To support longer delays in configuration, use the design solutions described in [UG470: 7 Series FPGA Configuration User Guide](#).
- Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.

eFUSE Programming Conditions

Table 64 lists the programming conditions specifically for eFUSE. For more information, see [UG470: 7 Series FPGA Configuration User Guide](#).

Table 64: eFUSE Programming Conditions⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
I _{FS}	V _{CCAUX} supply current	—	—	115	mA
t _j	Temperature range	15	—	125	°C

Notes:

- The FPGA must not be configured during eFUSE programming.

Notice of Disclaimer

The information disclosed to you hereunder (the "Materials") is provided solely for the selection and use of Xilinx products. To the maximum extent permitted by applicable law: (1) Materials are made available "AS IS" and with all faults, Xilinx hereby DISCLAIMS ALL WARRANTIES AND CONDITIONS, EXPRESS, IMPLIED, OR STATUTORY, INCLUDING BUT NOT LIMITED TO WARRANTIES OF MERCHANTABILITY, NON-INFRINGEMENT, OR FITNESS FOR ANY PARTICULAR PURPOSE; and (2) Xilinx shall not be liable (whether in contract or tort, including negligence, or under any other theory of liability) for any loss or damage of any kind or nature related to, arising under, or in connection with, the Materials (including your use of the Materials), including for any direct, indirect, special, incidental, or consequential loss or damage (including loss of data, profits, goodwill, or any type of loss or damage suffered as a result of any action brought by a third party) even if such damage or loss was reasonably foreseeable or Xilinx had been advised of the possibility of the same. Xilinx assumes no obligation to correct any errors contained in the Materials, or to advise you of any corrections or update. You may not reproduce, modify, distribute, or publicly display the Materials without prior written consent. Certain products are subject to the terms and conditions of the Limited Warranties which can be viewed at <http://www.xilinx.com/warranty.htm>; IP cores may be subject to warranty and support terms contained in a license issued to you by Xilinx. Xilinx products are not designed or intended to be fail-safe or for use in any application requiring fail-safe performance; you assume sole risk and liability for use of Xilinx products in Critical Applications: <http://www.xilinx.com/warranty.htm#critapps>.

AUTOMOTIVE APPLICATIONS DISCLAIMER

XILINX PRODUCTS ARE NOT DESIGNED OR INTENDED TO BE FAIL-SAFE, OR FOR USE IN ANY APPLICATION REQUIRING FAIL-SAFE PERFORMANCE, SUCH AS APPLICATIONS RELATED TO: (I) THE DEPLOYMENT OF AIRBAGS, (II) CONTROL OF A VEHICLE, UNLESS THERE IS A FAIL-SAFE OR REDUNDANCY FEATURE (WHICH DOES NOT INCLUDE USE OF SOFTWARE IN THE XILINX DEVICE TO IMPLEMENT THE REDUNDANCY) AND A WARNING SIGNAL UPON FAILURE TO THE OPERATOR, OR (III) USES THAT COULD LEAD TO DEATH OR PERSONAL INJURY. CUSTOMER ASSUMES THE SOLE RISK AND LIABILITY OF ANY USE OF XILINX PRODUCTS IN SUCH APPLICATIONS.